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Contents

Authors ٧ vii Conference Committee **NEW APPLICATIONS OF INFRARED MATERIALS AND TECHNOLOGY** 10179 04 Evaluation of undoped ZnS single crystal materials for x-ray imaging applications [10179-3] 10179 06 Superhydrophobic, infrared transmissive moth eye-like substrates for use in wet conditions [10179-5] **INFRARED WINDOW AND DOME TECHNOLOGY OVERVIEWS** 10179 09 Weibull analysis and area scaling for infrared windows [10179-8] 10179 0A Slow crack growth study of polycrystalline alumina and multispectral zinc sulfide [10179-9] 10179 OB Low-level background absorption in durable window materials [10179-10] OPTICAL/ELECTRICAL PROPERTIES OF INFRARED WINDOW AND DOME MATERIALS 10179 0D Scattering properties of hot isostatic pressed multispectral zinc sulfide [10179-12] 10179 OE High-temperature material characterization for multispectral window [10179-13] ADVANCES IN MID-WAVELENGTH INFRARED WINDOW AND DOME MATERIALS 10179 OF Refractive index of infrared-transparent polycrystalline alumina [10179-14] 10179 0G Strength characteristics of transparent alumina and spinel ceramics [10179-15] 10179 01 Conformal ALON and spinel windows [10179-17] 10179 OJ Scale up of large ALON and spinel windows [10179-18]

INFRARED WINDOW AND DOME PROCESSING AND MANUFACTURING TECHNOLOGY I 10179 OK Drying step optimization to obtain large-size transparent magnesium-aluminate spinel **samples** [10179-19] 10179 OL Development of optical ceramic materials for infrared applications by optimizing sintering **conditions** [10179-20] 10179 OM Manufacturing and metrology for IR conformal windows and domes [10179-21] INFRARED WINDOW AND DOME PROCESSING AND MANUFACTURING II 10179 ON **18x36x1.5** inch sapphire panels for visible and infrared windows [10179-22] 10179 00 Refractive index homogeneity TWE effect on large aperture optical systems [10179-23] 10179 OP New advancements in freeform optical metrology [10179-24] 10179 0Q Grinding and polishing of conformal windows and domes [10179-25]

Authors

Numbers in the index correspond to the last two digits of the seven-digit citation identifier (CID) article numbering system used in Proceedings of SPIE. The first five digits reflect the volume number. Base 36 numbering is employed for the last two digits and indicates the order of articles within the volume. Numbers start with 00, 01, 02, 03, 04, 05, 06, 07, 08, 09, 0A, 0B...0Z, followed by 10-1Z, 20-2Z, etc.

Aggarwal, Ishwar D., 06 Arida, Marvin-Ray, 0E Baldwin, Lawrence, OF Baronowski, Meghan, OF Bayya, Shyam S., 06 Blalock, Todd, 0M Blockburger, Clark, 0N Boyd, Darryl A., 06 Brunelle, Matt, 0M Busse, Lynda E., 06 Cambrea, Lee R., OA, OF DeFisher, Scott, OP

Felde, Nadja, 0D Ferralli, Ian, 0M Fess, Edward, 0Q Frantz, Jesse A., 06 Gannon, John J., Jr., 0F, 0G Goldman, Lee M., 01, 0J Goodrich, Steven M., 0A Harris, Daniel C., 09, 0A, 0F, 0G Isogai, Masafumi, OL Jang, Woo-Yong, 0E Jha, Santosh, Ol, OJ Johnson, Linda F., OF Joseph, Shay, OD Kashalikar, Uday, 0J Kim, Woohong, 06 Ku, Zahyun, 0E Kunkel, John D., 0F Lallemant, Lucile, OK Lynch, Timothy, 0M

Lynn, Kelvin G., 04 Matthews, Greg, OP, OQ

McCloy, John S., 04 Medicus, Kate, 0M Montgomery, Matthew, 0N Myer, Brian, 0M Neff, B., 0O Parish, Mark V., 0A, 0F, 0G Park, James, 0E Pascucci, Marina R., OA, OF, OG Petit, Johan, OK Poston, William B., OF Ramisetty, Mohan, OI, OJ Ross, James, OP, OQ Saleh, Muad, 04 Sanghera, Jasbinder S., 06 Sano, Masahiko, OL Sastri, Suri, OI, OJ

Schröder, Sven, 0D Shienmann, Arit, 0D Smith, Mark, 01 Stout, M., 00 Thomas, M. E., OB Trost, Marcus, 0D Urbas, Augustine M., 0E Wen, Tzu-Chien, 0F Zelmon, David E., 0F

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- New Applications of Infrared Materials and Technology Melissa Stout, II-VI Optical Systems (United States)
- 2 Infrared Window and Dome Technology Overviews Brian J. Zelinski, Raytheon Missile Systems (United States)

- 3 Optical/Electrical Properties of Infrared Window and Dome Materials Daniel C. Harris, Naval Air Warfare Center Weapons Division (United States)
- 4 Advances in Mid-wavelength Infrared Window and Dome Materials **W. Howard Poisl**, Raytheon Missile Systems (United States)
- Infrared Window and Dome Processing and Manufacturing Technology I
 Marc Tricard, Zygo Corporation (United States)
- 6 Infrared Window and Dome Processing and Manufacturing II

 Marc Tricard, Zygo Corporation (United States)
- 7 Testing and Modeling of Environmental Damage **Ted Turnquist**, Meller Optics, Inc. (United States)